P1450.4 meeting minutes - 05/25/05

Attendees: Jim O'Reilly, Daniel Fan, Tony Taylor, Jose Santiago, Bob Roberts, Ernie Wahl, Dave Dowding

Not present: Tom Micek, Doug Sprague, Yuhai Ma, Eric Nguyen, Chris Nelson, Oscar Rodriguez, Steve Lill, Don Organ, Jim Mosley

Summary:

- Some P1450.3 news (from Tony). Will likely need to request IEEE reauth (since the PAR + extension expires at end of this year).
- Review syntax document. (D14). Several points were noted:
    - Question about the underlined options in the attributes for variables of the TestMethodDefs block. Answer: underlined attributes are the defaults if no attributes are explicitly specified.
    - A lengthy discussion about the Category/Selector keywords of the TestObjectDefs and TestFlow blocks. The main question is whether we want to have the Category/Selector specified globally (so that the most recent setting is active for subsequent blocks, unless changed), or scoped (as part of a particular block – probably a TestObject or TestMethod block). Much discussion about the pros and cons of each, and the impact on runtime performance vs. maintainability. We agreed to review how this is handled by the various ATE SW systems currently available, and use that data to help arrive at a consensus on this issue.
    - Some discussion about binning and binmaps. Nothing substantive was decided (yet).
    - It was pointed out that the "Exception" keyword of an "exit_port_stmt" should probably be raised to the level of the TestProgram block "On<Event>" statements. After some discussion, we concluded that change should be made; Tony will update the document.
    - The actions specified by "exit_port_stmt" need to be expanded; in past drafts of the syntax, more actions than those listed here were included. We need to reconcile this draft of the syntax (D14) with the capabilities that were present in previous drafts – both on this issue, and in general.
    - In the "Real" types, we agreed to change the "Complex" type (intended to be used with combinations of other types – such as Volts/Deg. C) to "General" since "Complex" can have specific meaning, especially if dealing with analog or mixed-signal tests (i.e., complex numbers).
- For reference STIL .4 information can be found at the IEEE STIL website: http://grouper.ieee.org/groups/1450/ (select the P1450.4 link from the table) or use the direct link http://grouper.ieee.org/groups/1450/dot4/index.html